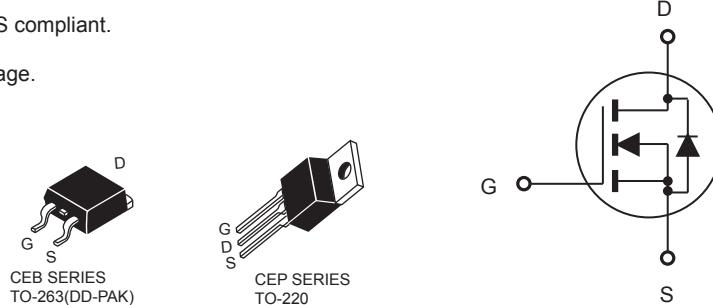


## N-Channel Enhancement Mode Field Effect Transistor

### FEATURES

- 55V, 108.5A,  $R_{DS(ON)} = 8.5m\Omega$  @ $V_{GS} = 10V$ .
- Super high dense cell design for extremely low  $R_{DS(ON)}$ .
- High power and current handing capability.
- Lead-free plating ; RoHS compliant.
- TO-220 & TO-263 package.



### ABSOLUTE MAXIMUM RATINGS $T_C = 25^\circ C$ unless otherwise noted

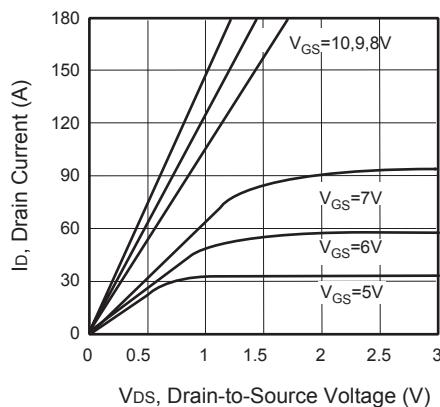
Parameter	Symbol	Limit	Units
Drain-Source Voltage	$V_{DS}$	55	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current-Continuous @ $T_C = 25^\circ C$ @ $T_C = 100^\circ C$	$I_D$	108.5 76.7	A
Drain Current-Pulsed <sup>a</sup>	$I_{DM}$	434	A
Maximum Power Dissipation @ $T_C = 25^\circ C$ - Derate above 25 $^\circ C$	$P_D$	200 1.3	W W/ $^\circ C$
Repetitive Avalanche Energy	$E_{AR}$	1.38	mJ
Single Pulsed Avalanche Energy <sup>d</sup>	$E_{AS}$	319	mJ
Single Pulsed Avalanche Current <sup>d</sup>	$I_{AS}$	68	A
Operating and Store Temperature Range	$T_J, T_{stg}$	-55 to 175	$^\circ C$

### Thermal Characteristics

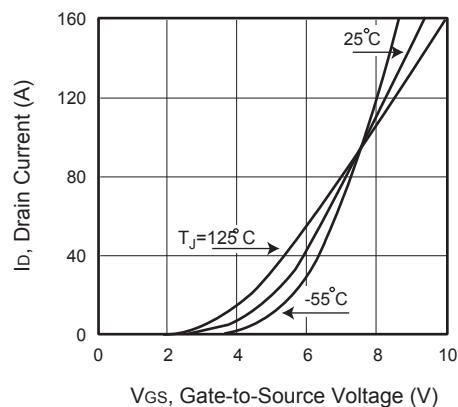
Parameter	Symbol	Limit	Units
Thermal Resistance, Junction-to-Case	$R_{JC}$	0.75	$^\circ C/W$
Thermal Resistance, Junction-to-Ambient	$R_{JA}$	62.5	$^\circ C/W$

**Electrical Characteristics**  $T_C = 25^\circ\text{C}$  unless otherwise noted

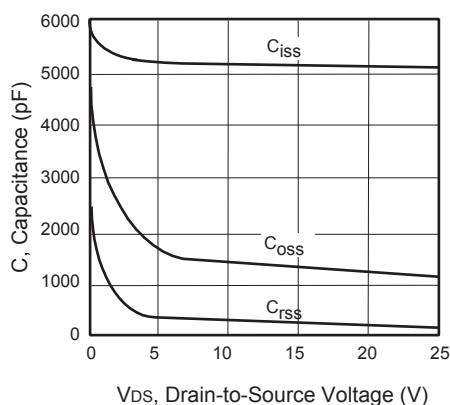
Parameter	Symbol	Test Condition	Min	Typ	Max	Units
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	55			V
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 55\text{V}, V_{\text{GS}} = 0\text{V}$		1		$\mu\text{A}$
Gate Body Leakage Current, Forward	$I_{\text{GSSF}}$	$V_{\text{GS}} = 20\text{V}, V_{\text{DS}} = 0\text{V}$		100		nA
Gate Body Leakage Current, Reverse	$I_{\text{GSSR}}$	$V_{\text{GS}} = -20\text{V}, V_{\text{DS}} = 0\text{V}$		-100		nA
<b>On Characteristics</b> <sup>b</sup>						
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = 250\mu\text{A}$	2		4	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 62\text{A}$		6.5	8.5	$\text{m}\Omega$
<b>Dynamic Characteristics</b> <sup>c</sup>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{DS}} = 25\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		5040		pF
Output Capacitance	$C_{\text{oss}}$			1115		pF
Reverse Transfer Capacitance	$C_{\text{rss}}$			35		pF
<b>Switching Characteristics</b> <sup>c</sup>						
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 28\text{V}, I_D = 62\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 4.5\Omega$		27	54	ns
Turn-On Rise Time	$t_r$			14	28	ns
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$			68	136	ns
Turn-Off Fall Time	$t_f$			19	38	ns
Total Gate Charge	$Q_g$	$V_{\text{DS}} = 44\text{V}, I_D = 62\text{A}, V_{\text{GS}} = 10\text{V}$		102.3	136	nC
Gate-Source Charge	$Q_{\text{gs}}$			23.1		nC
Gate-Drain Charge	$Q_{\text{gd}}$			23.1		nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
Drain-Source Diode Forward Current	$I_S$				108.5	A
Drain-Source Diode Forward Voltage <sup>b</sup>	$V_{\text{SD}}$	$V_{\text{GS}} = 0\text{V}, I_S = 62\text{A}$			1.3	V
Notes : a.Repetitive Rating : Pulse width limited by maximum junction temperature b.Pulse Test : Pulse Width $\leq 300\mu\text{s}$ , Duty Cycle $\leq 2\%$ . c.Guaranteed by design, not subject to production testing. d.L = 138 $\mu\text{H}$ , $I_{\text{AS}} = 68\text{A}$ , $V_{\text{DD}} = 25\text{V}$ , $R_G = 25\Omega$ , Starting $T_J = 25^\circ\text{C}$						



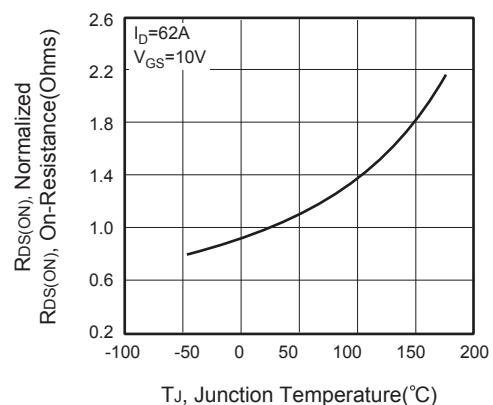
**Figure 1. Output Characteristics**



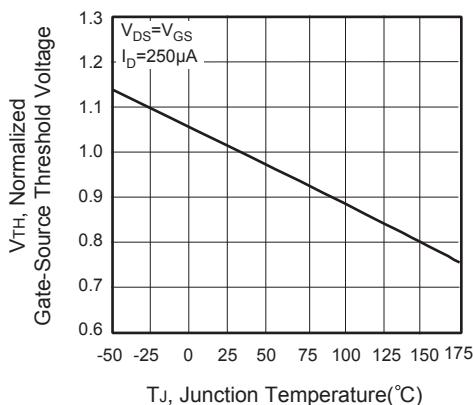
**Figure 2. Transfer Characteristics**



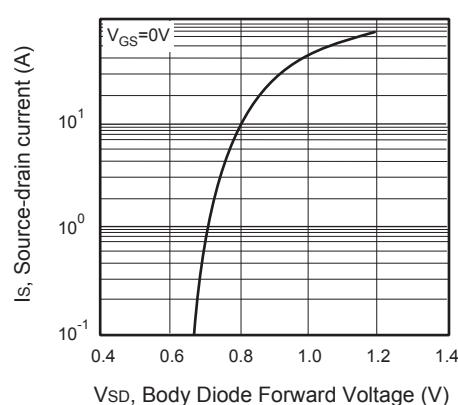
**Figure 3. Capacitance**



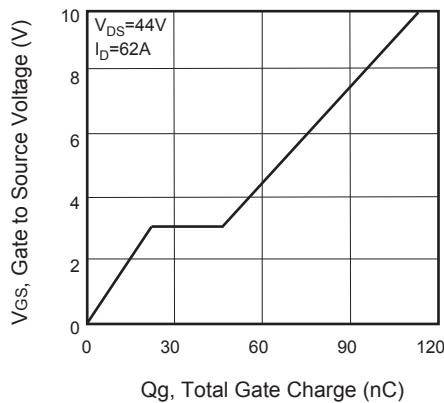
**Figure 4. On-Resistance Variation with Temperature**



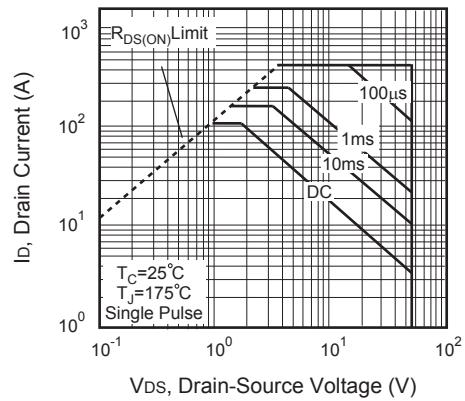
**Figure 5. Gate Threshold Variation with Temperature**



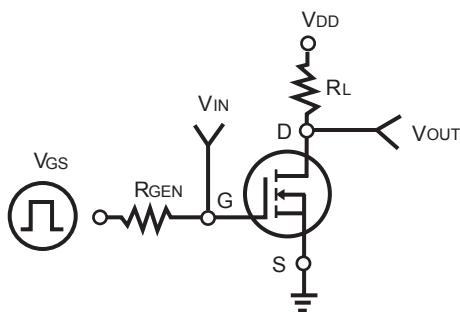
**Figure 6. Body Diode Forward Voltage Variation with Source Current**



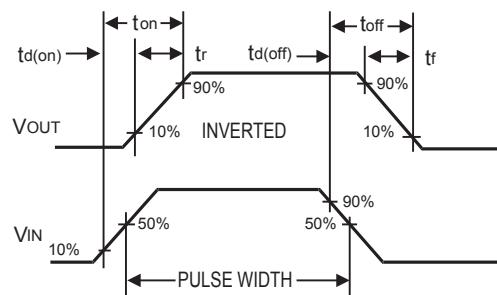
**Figure 7. Gate Charge**



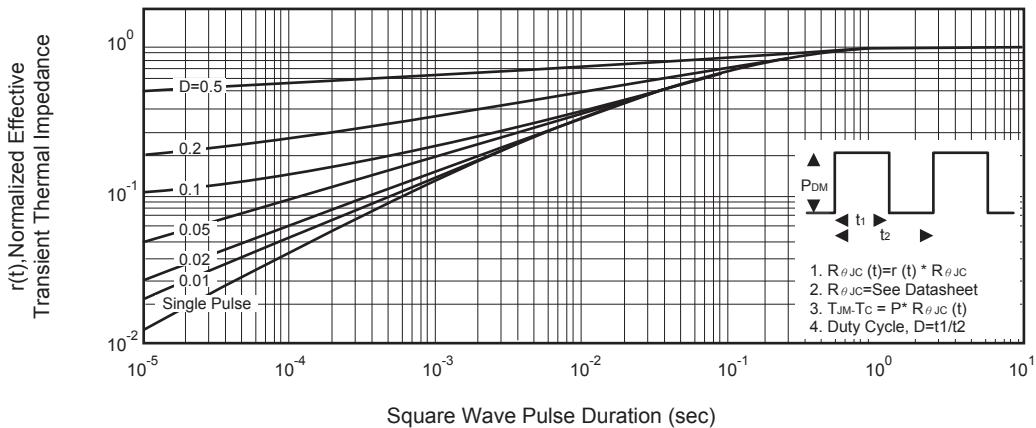
**Figure 8. Maximum Safe Operating Area**



**Figure 9. Switching Test Circuit**



**Figure 10. Switching Waveforms**



**Figure 11. Normalized Thermal Transient Impedance Curve**